

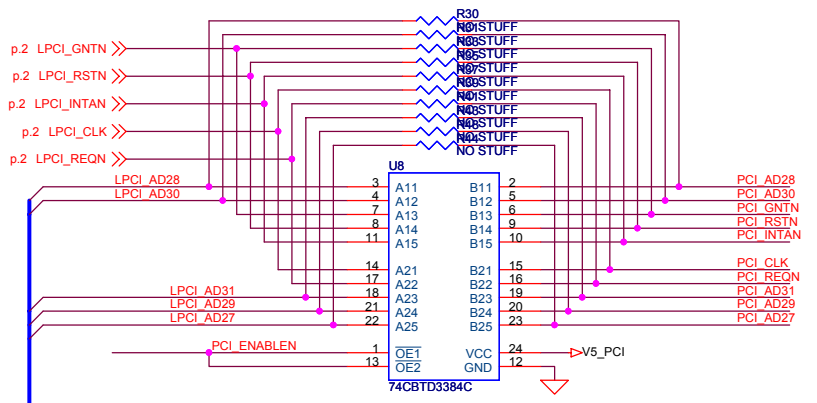
EPM1270F256C5

Layout Note:  
 Create Silk Screen box for  
 these four test points, label  
 it "ACTIVE IO TEST POINTS"

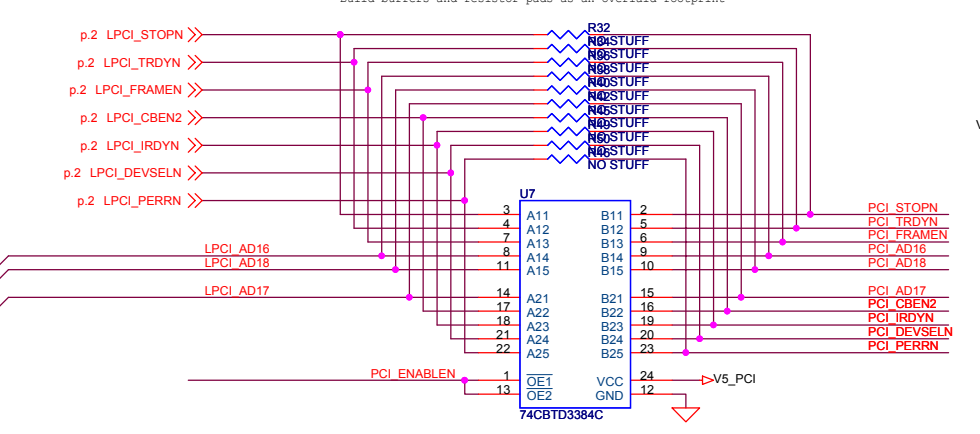


3590 N. 1st St., Suite 210  
 San Jose, CA 95134  
 (408) 228-5580 Fax (408) 228-5590  
 www.nuvation.com

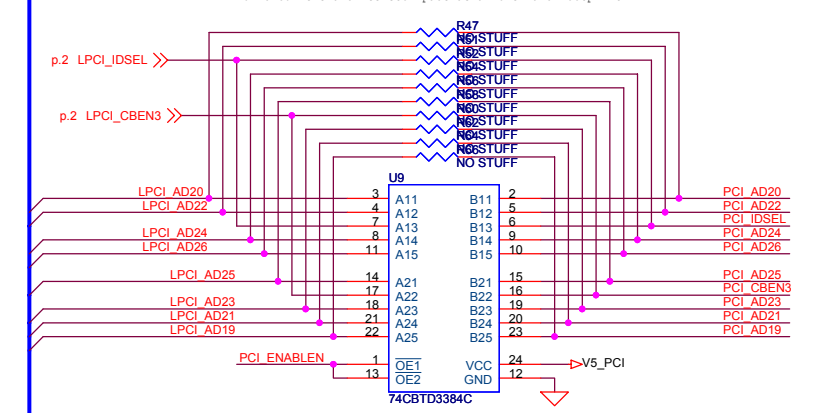
Layout Note:  
Build buffers and resistor pads as an overlaid footprint



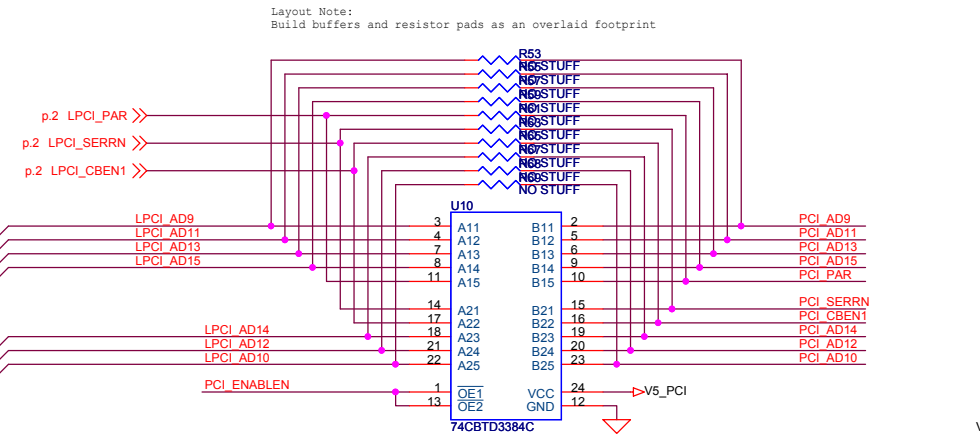
Layout Note:  
Build buffers and resistor pads as an overlaid footprint



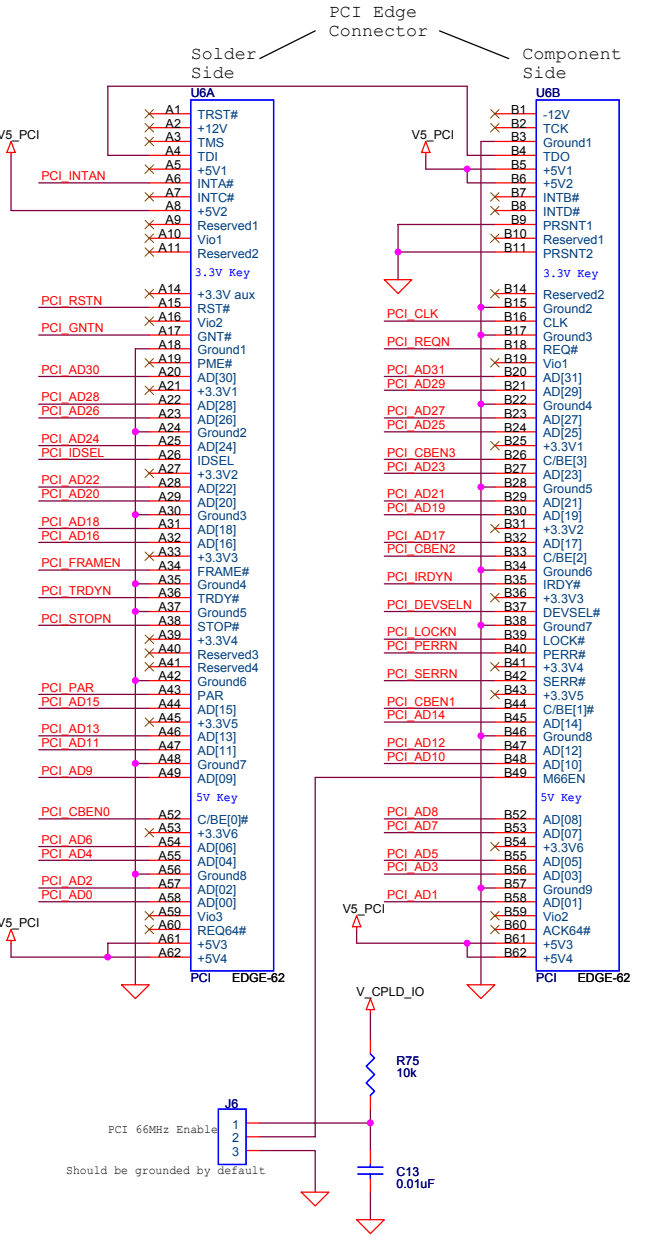
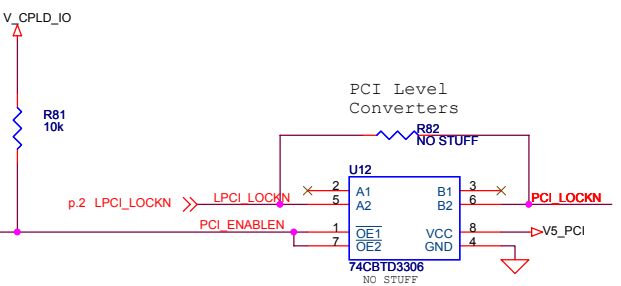
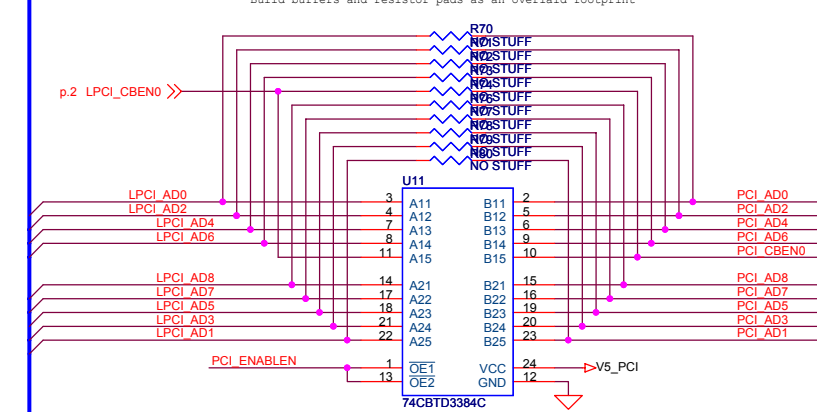
Layout Note:  
Build buffers and resistor pads as an overlaid footprint



Layout Note:  
Build buffers and resistor pads as an overlaid footprint

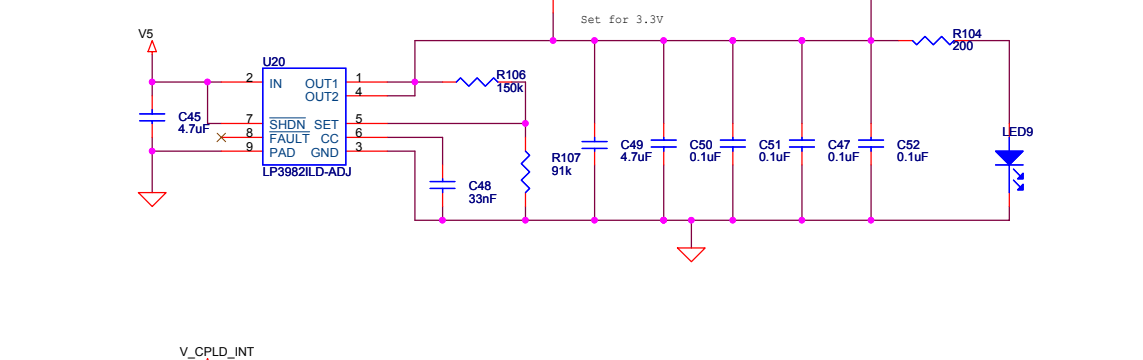
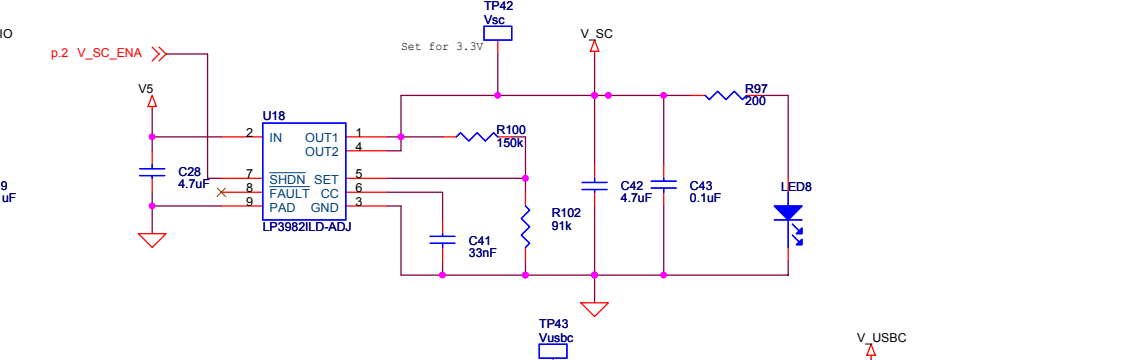
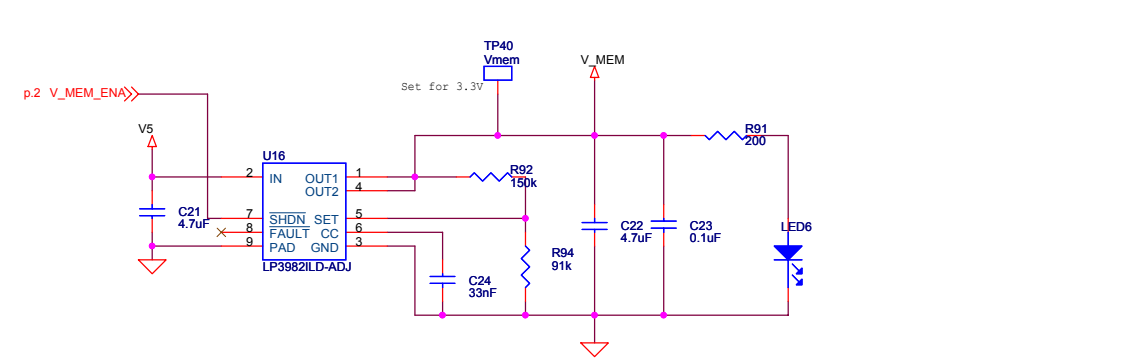
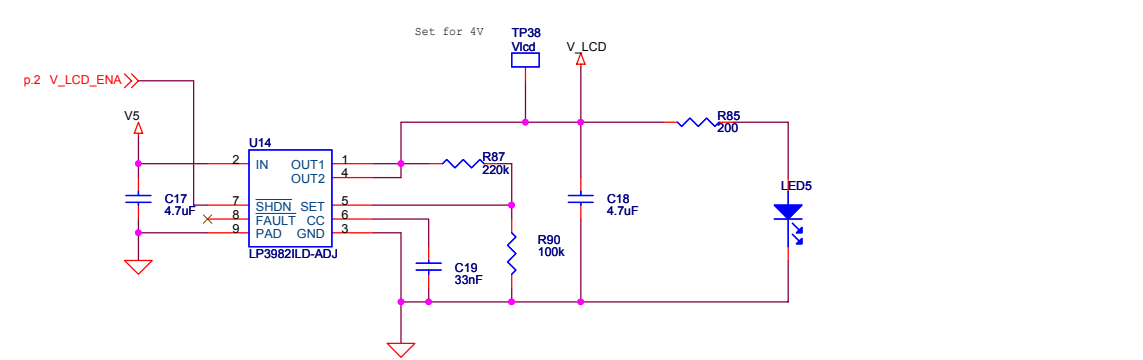
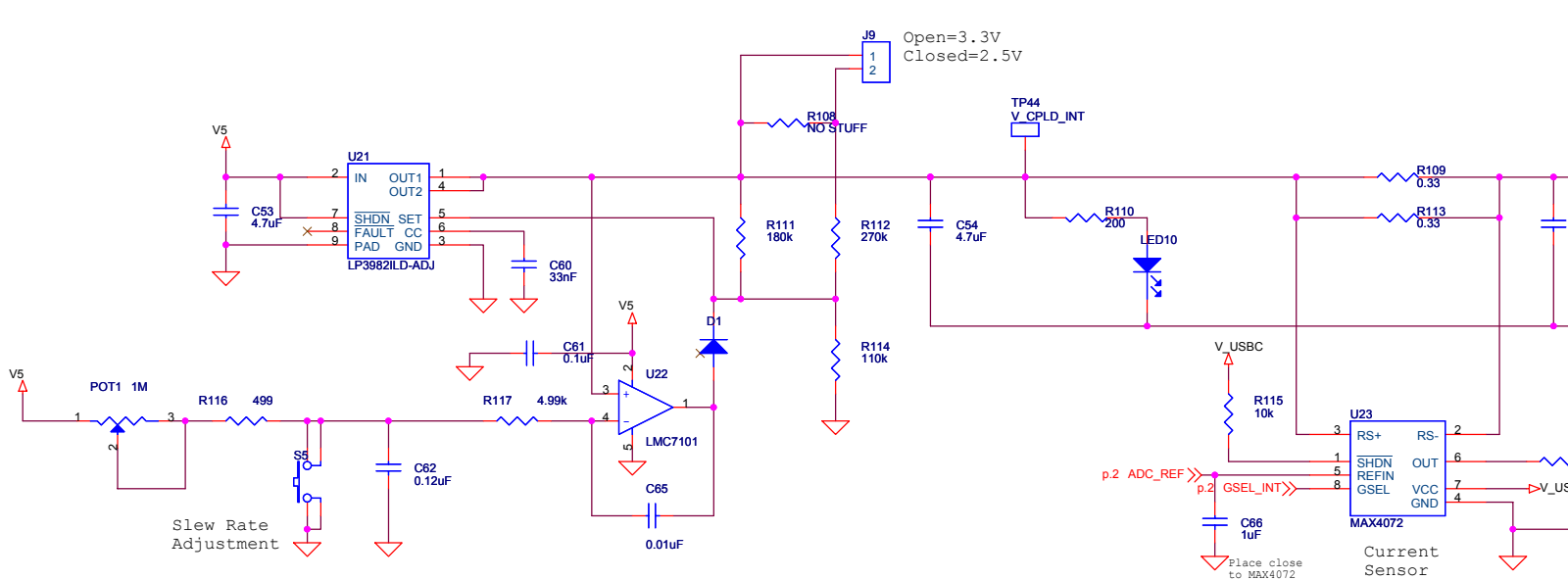
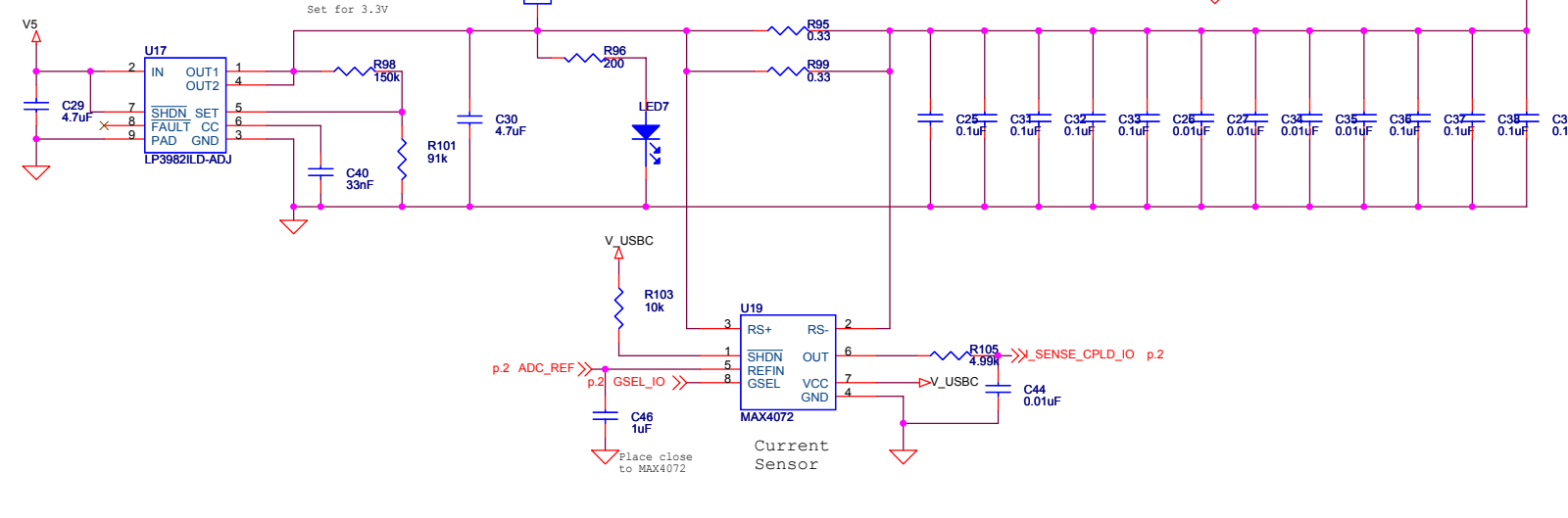
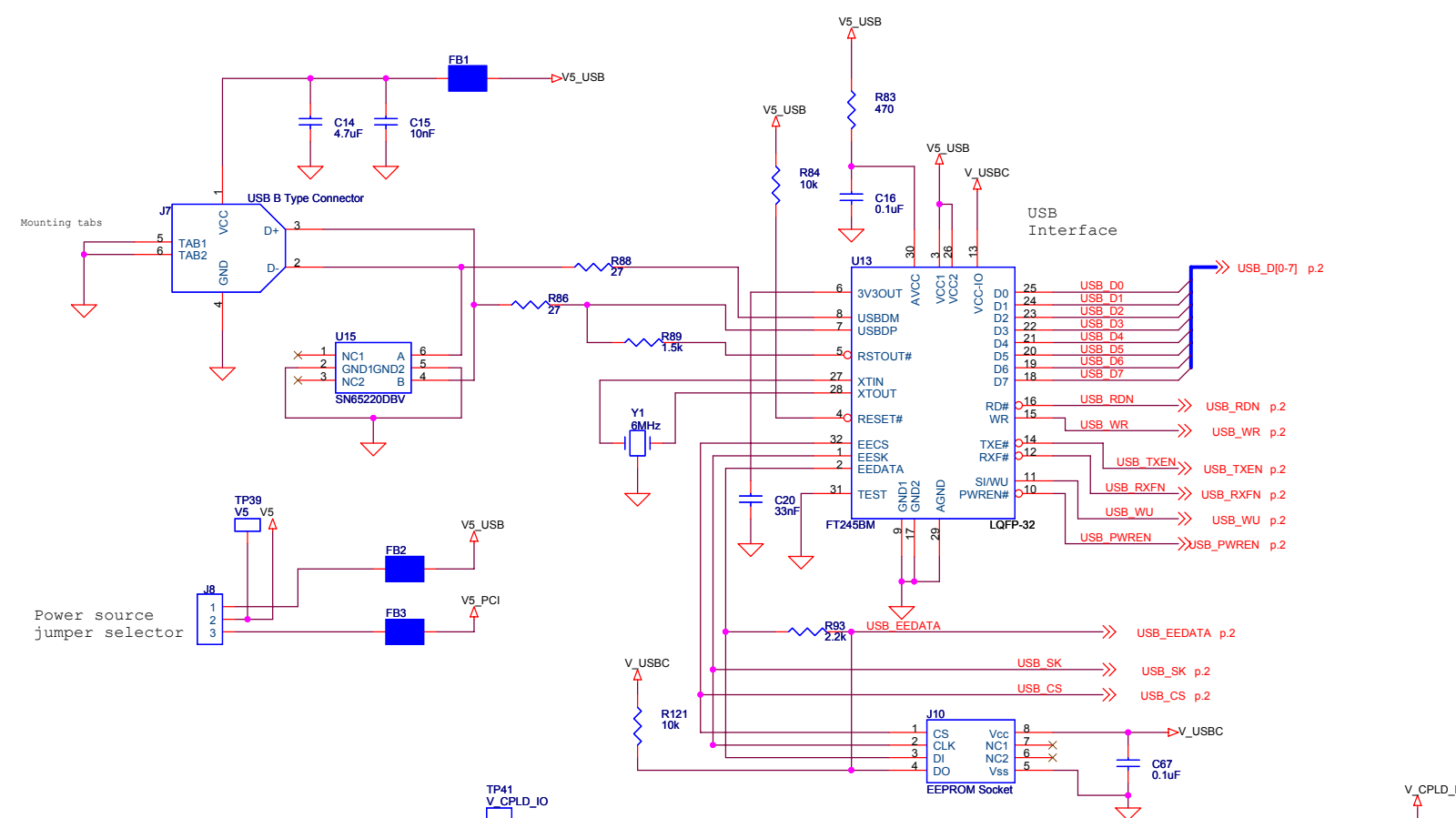


Layout Note:  
Build buffers and resistor pads as an overlaid footprint



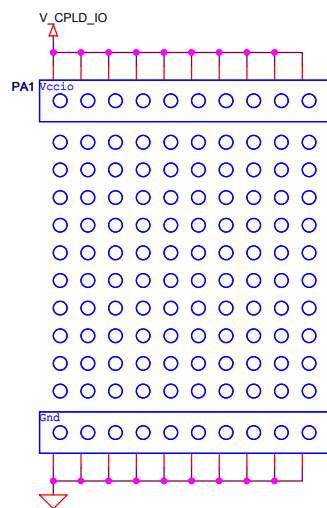
p.2 LPCI\_AD[0-31] >>

p.2 PCI\_ENABLEN >>



**NUVATION**  
 3590 N. 1st St., Suite 210  
 San Jose, CA 95134  
 (408) 228-5580 Fax (408) 228-5590  
 www.nuvation.com

Project **ALT06 - MAX II Eval**  
 Page Title **USB and Power Supplies**  
 Size **C** Doc. No. **<Doc>** Rev **1.6**  
 Date: **Tuesday, August 31, 2004** Sheet **4** of **5**



This symbol represents the prototype area consisting of:  
 - 10x10 grid of no-connect through-hole test points  
 - 10 through-hole test points connected to Vccio  
 - 10 through-hole test points connected to ground

LAYOUT NOTE: Silkscreen this prototype area to mark the area as pictured